Notice of References Cited Application/Control No. 10/727,187 Applicant(s)/Patent Under Reexamination JACK ET AL. Examiner Faye Polyzos 2884 Applicant(s)/Patent Under Reexamination JACK ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-5,171,733 A	12-1992	Hu, Qing	505/161
*	В	US-5,850,098 A	12-1998	Butler et al.	257/467
*	С	US-6,459,084 B1	10-2002	Boreman et al.	250/349
*	D	US-2003/0222217 A1	12-2003	Luukanen, Arttu	250/336.2
*	Ε	US-6,777,684 B1	08-2004	Volkov et al.	250/341.1
*	F	US-6,316,770 B1	11-2001	Ouvrier-Buffet et al.	250/338.1
*	G	US-6,292,140 B1	09-2001	Osterman, David P.	343/700MS
*	Н	US-2005/0067576 A1	03-2005	Caria, Mario	250/370.08
		US-			
	J	US-			
	К	US-			
	L	US-		1	
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Z					
	0					
	Ρ				•	
	σ					
	R					
	S					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Rice et al., "High-Tc Superconducting Antenna-Coupled Microbolometer on Silicon", SPIE Proceedings, The International Society for Optical Engineering U.S.A., 1994, Vol. 2159, pages 98-109, XP009041389.
	v	
	w	
	х	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.